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(12) **United States Design Patent**
Kitayama

(10) **Patent No.:** **US D745,687 S**

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(54) **PROBE FOR AN ULTRASONIC DIAGNOSIS APPARATUS**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** **24-01**

(52) **U.S. Cl.**
USPC **D24/187**

(58) **Field of Classification Search**
USPC D24/133, 137, 158, 186, 187; D10/78;
600/407, 446, 439, 461; 378/98.7,
378/98.8, 189
CPC A61B 8/445; A61B 8/4455; A61B 8/4461
See application file for complete search history.

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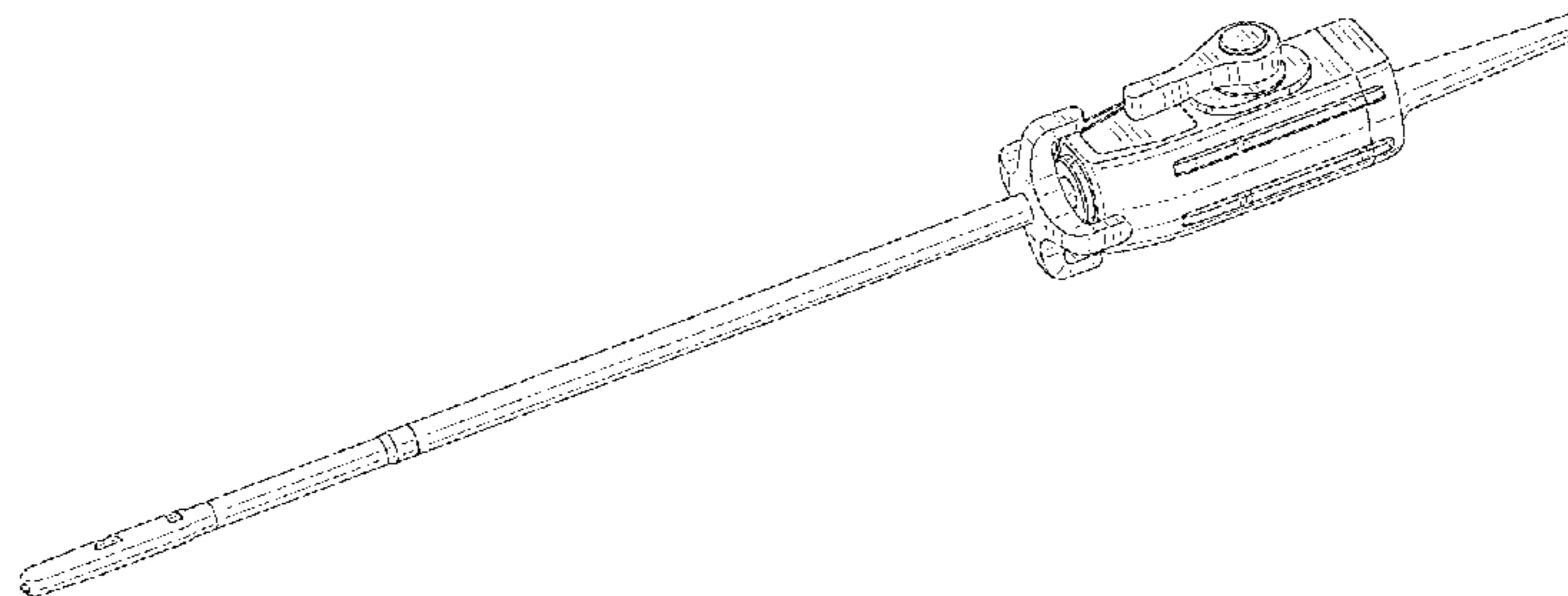
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(57) **CLAIM**
The ornamental design for a probe for an ultrasonic diagnosis apparatus, as shown and described.

DESCRIPTION

FIG. 1 is a front, top and left side perspective view of a probe for an ultrasonic diagnosis apparatus, showing my new design;
FIG. 2 is a rear, top and right side perspective view thereof;
FIG. 3 is a front view thereof;
FIG. 4 is a left side view thereof;
FIG. 5 is a right side view thereof;
FIG. 6 is a top view thereof;
FIG. 7 is a bottom view thereof;
FIG. 8 is a rear view thereof;
FIG. 9 is a cross sectional view thereof, taken along the line 9-9 in FIG. 4 with its internal mechanisms omitted;
FIG. 10 is an enlarged fragmented view thereof, taken along the line 10 of FIG. 3;
FIG. 11 is an enlarged fragmented view thereof, taken along the line 11 of FIG. 3;
FIG. 12 is an enlarged left side view thereof;
FIG. 13 is an enlarged fragmented view thereof, taken along the line 13 of FIG. 6;
FIG. 14 is an enlarged fragmented view thereof, taken along the line 14 of FIG. 6;
FIG. 15 is an enlarged fragmented view thereof, taken along the line 15 of FIG. 9;
FIG. 16 is an enlarged fragmented view thereof, taken along the line 16 of FIG. 9; and,
FIG. 17 is a perspective view thereof in an alternate condition of use.
The broken lines in FIGS. 3, 6, 9, 10, 11, 13, 14, 15 and 16 are included to indicate the point at which the magnified view is cut off. The broken lines showing the inner portions in FIGS. 9, 15, 16 are included for the purpose of illustrating unclaimed portions of the probe. None of the broken lines form part of the claimed design.

1 Claim, 9 Drawing Sheets



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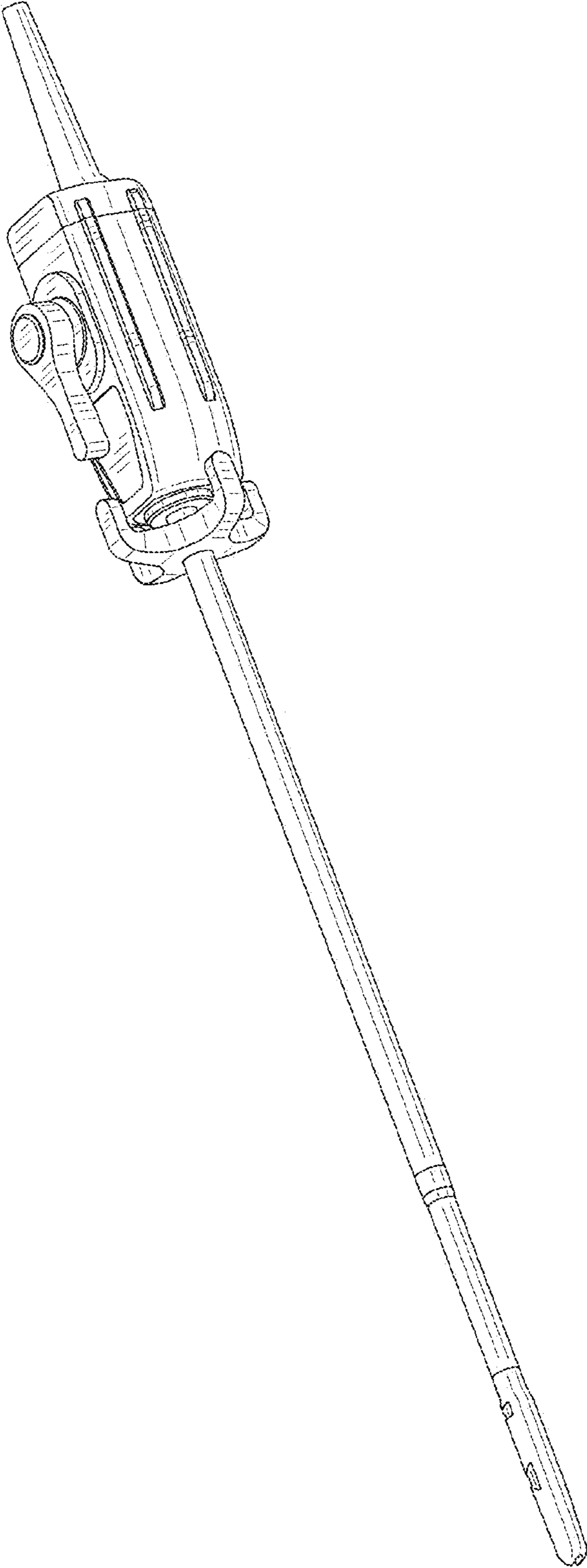


Fig. 1

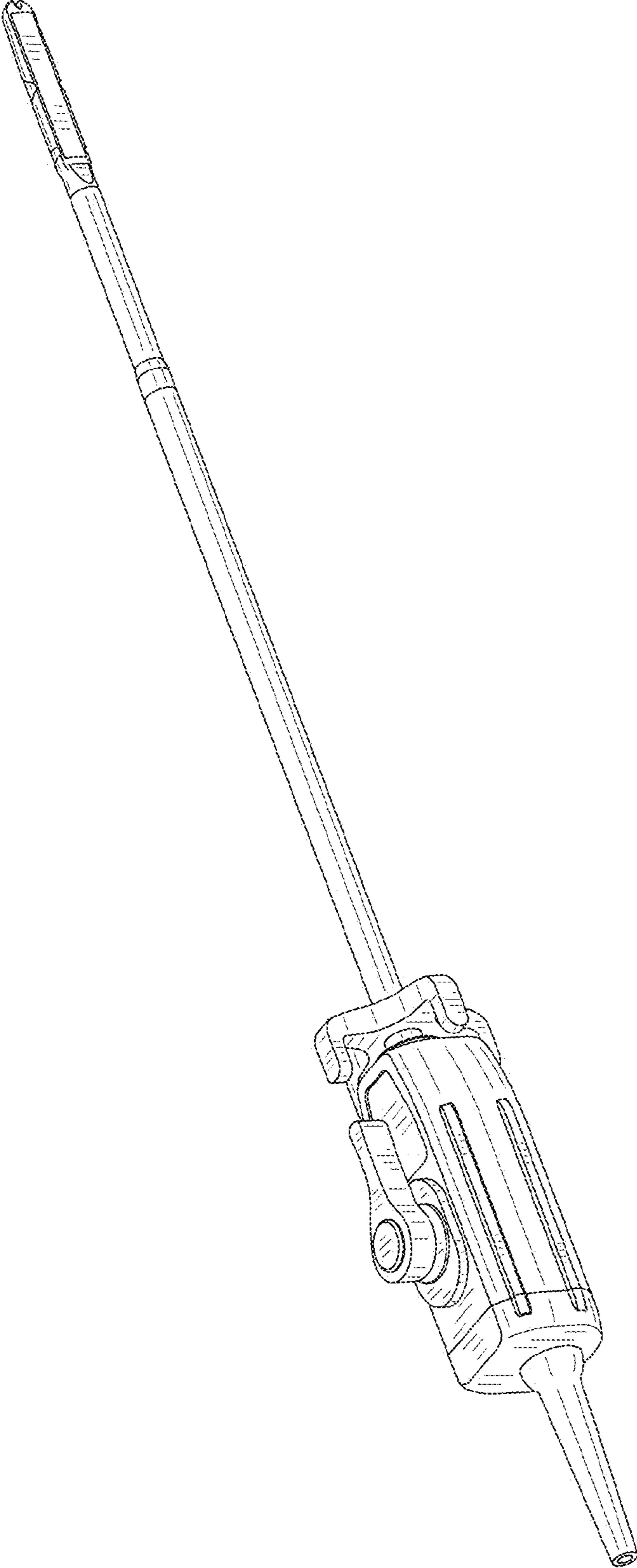


Fig. 2

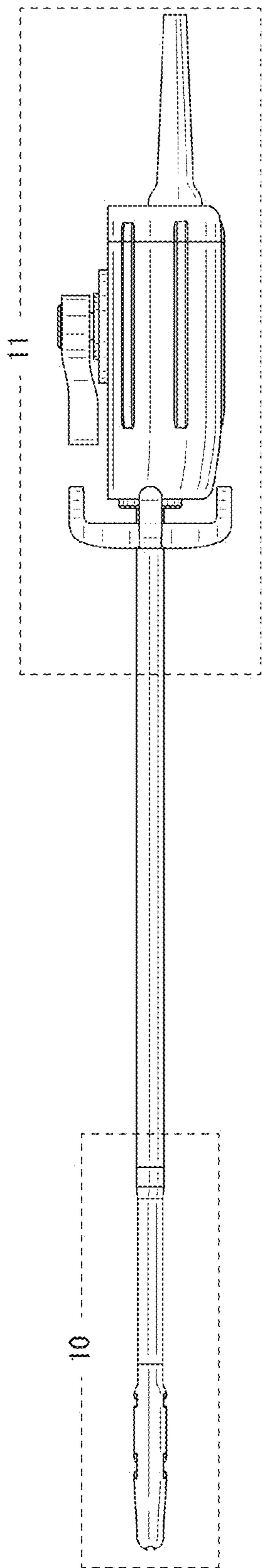


Fig. 3

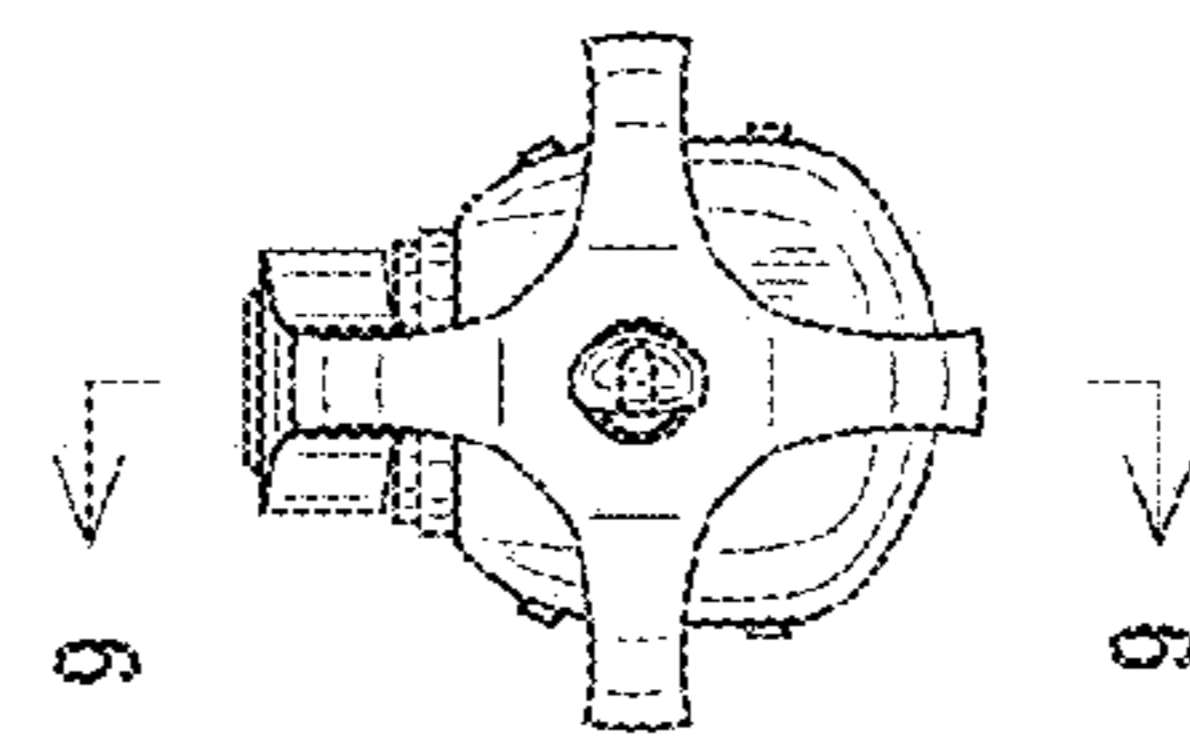


Fig. 4

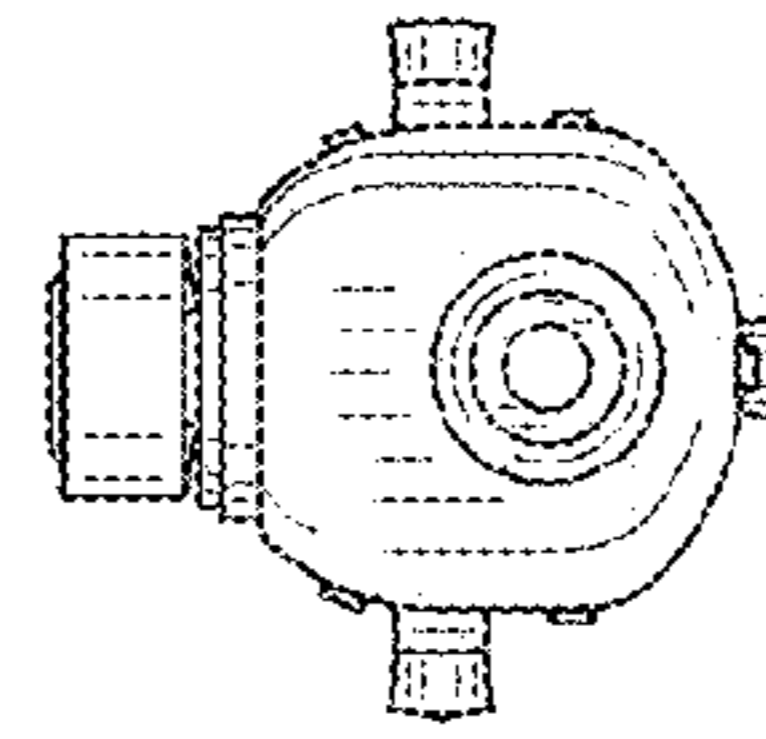


Fig. 5

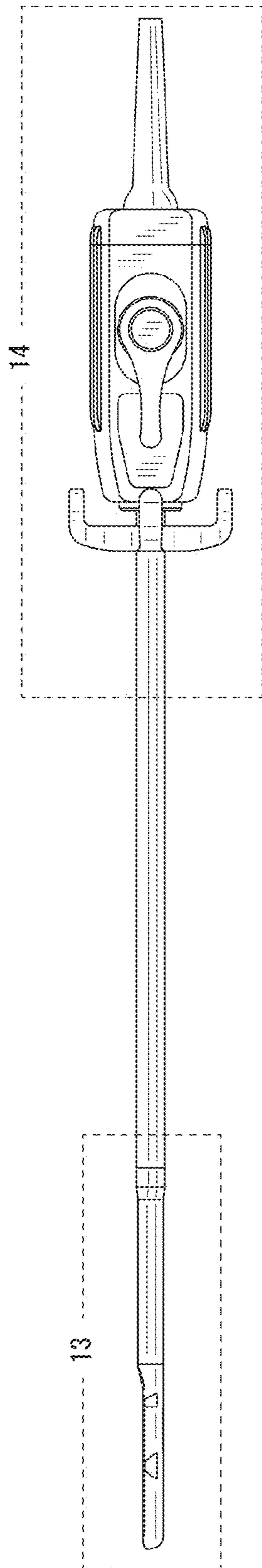


Fig. 6

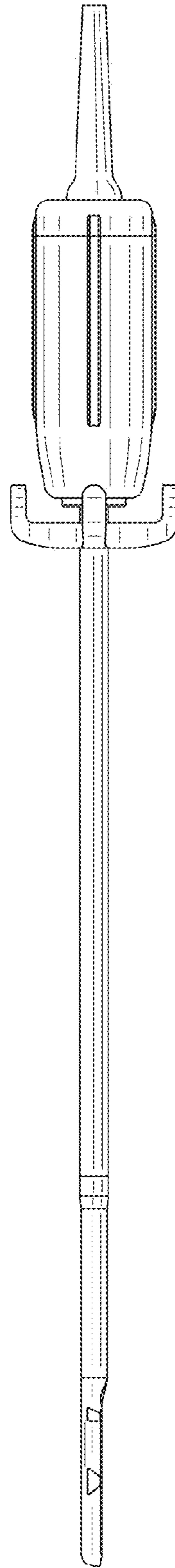


Fig. 7

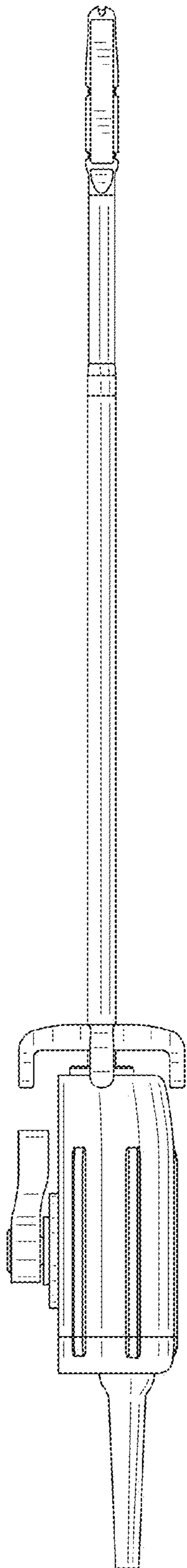


Fig. 8

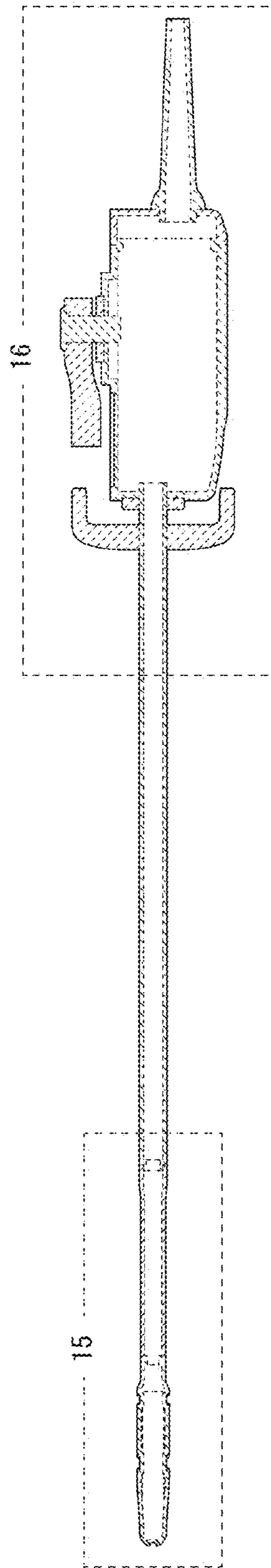


Fig. 9

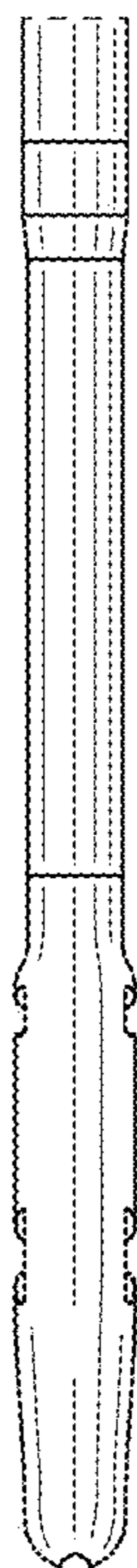


Fig. 10

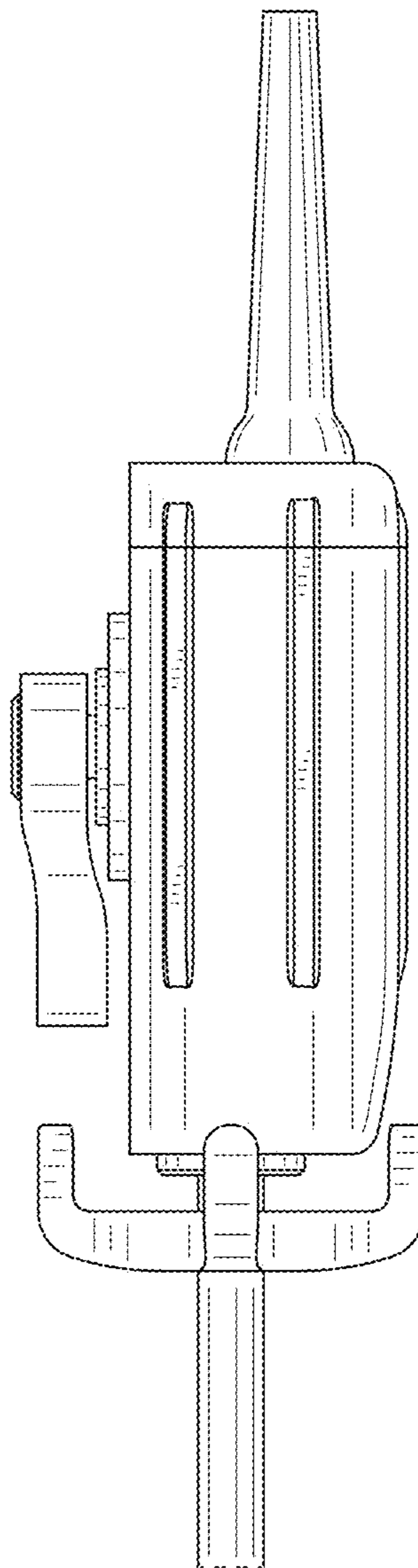


Fig. 11

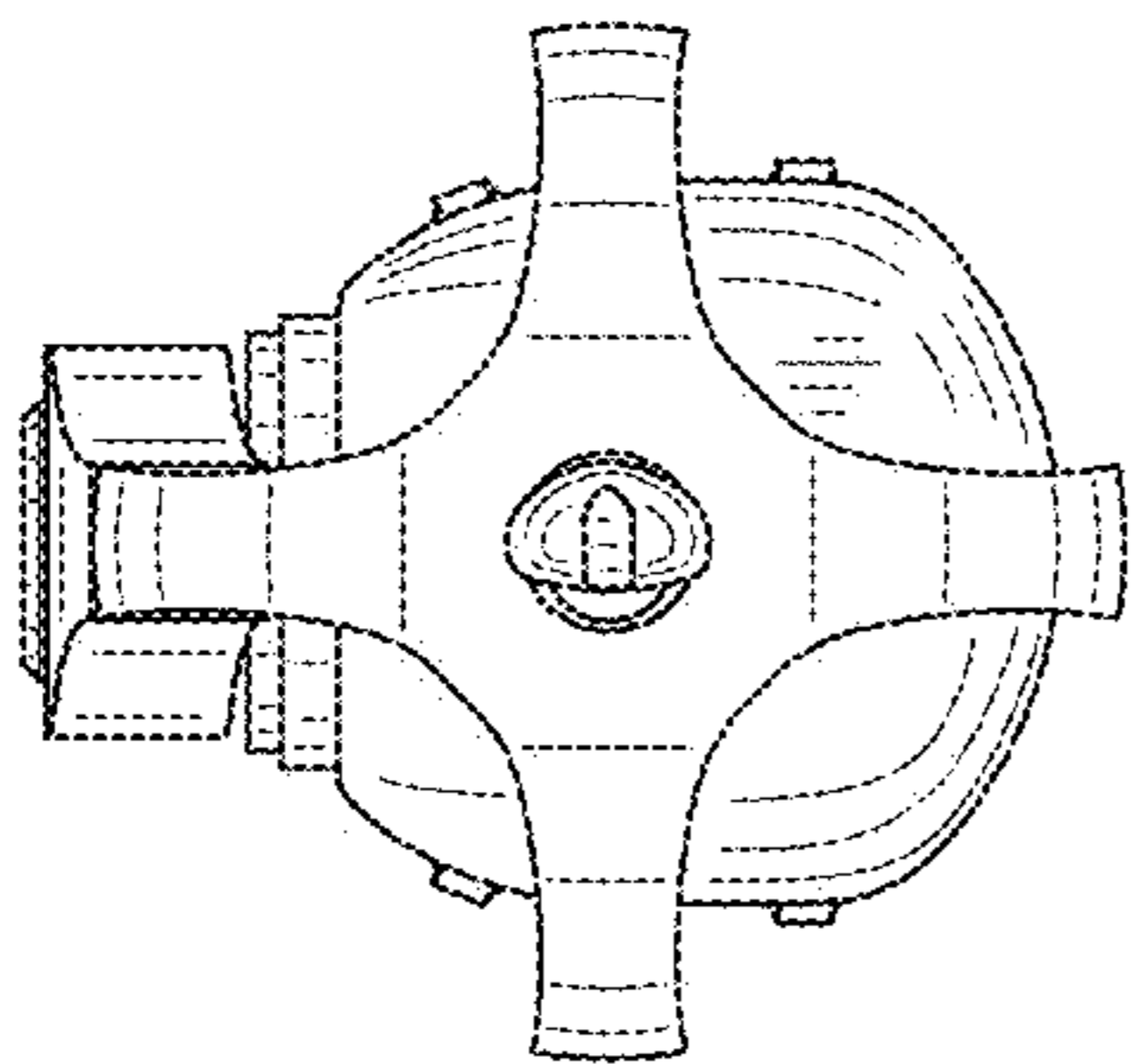


Fig. 12



Fig. 13

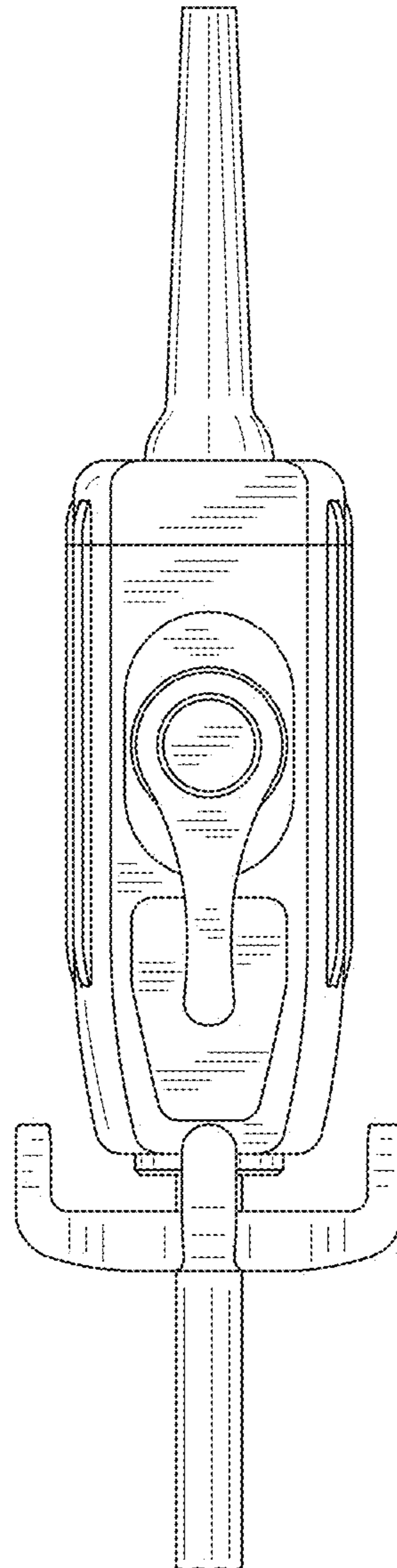


Fig. 14

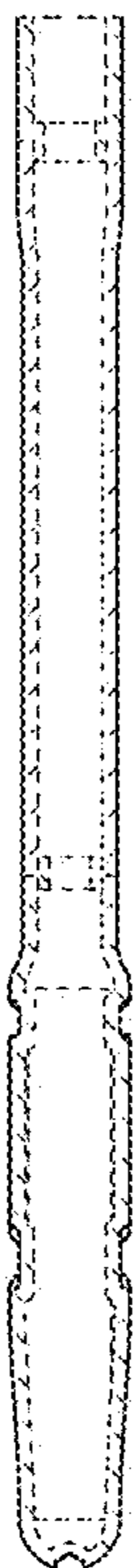


Fig. 15

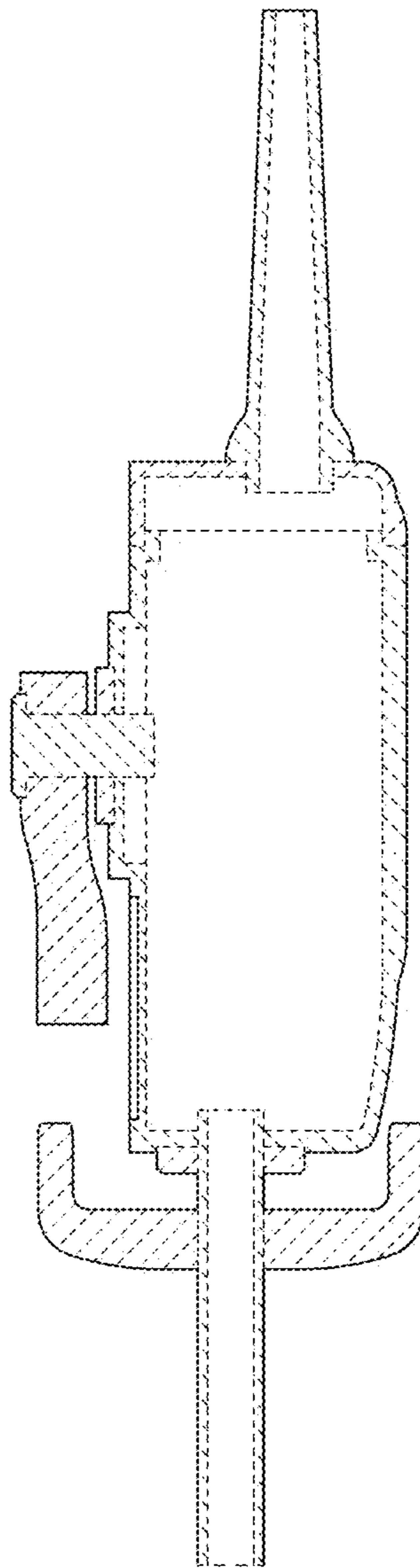


Fig. 16

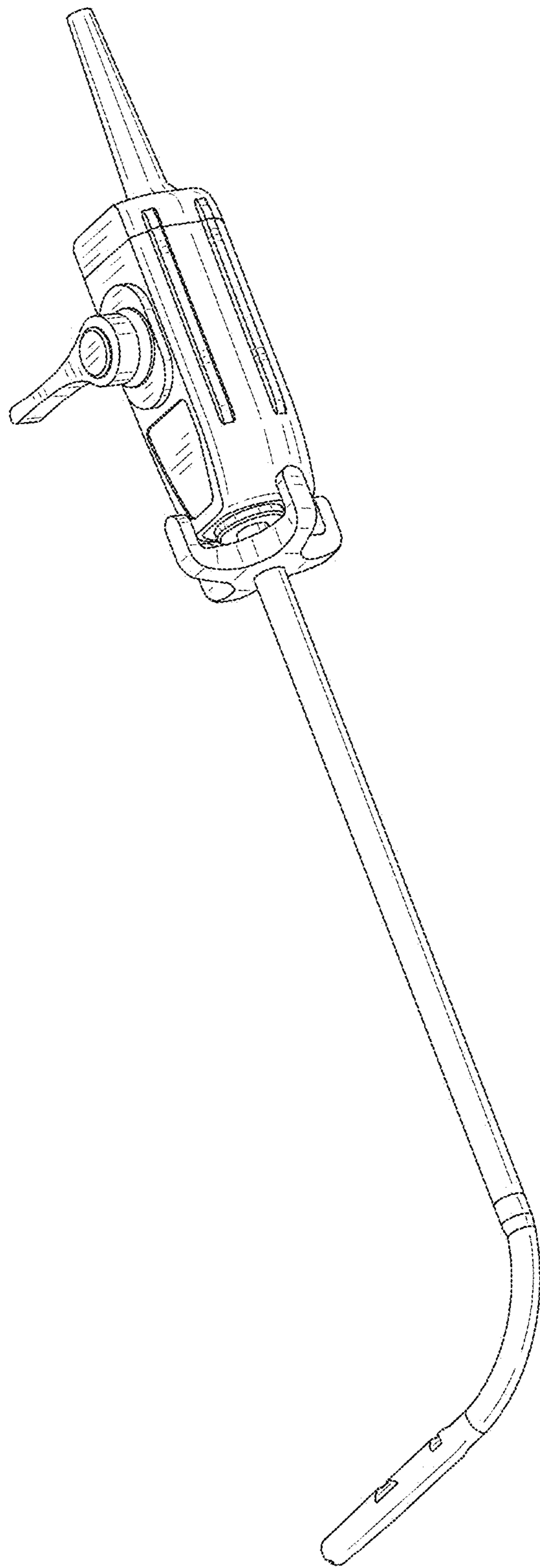


Fig. 17